

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of: **Spencer M. Gold, et al.**

Serial No.: **Not Yet Assigned**

Filed: **Herewith**

For: **AN INTEGRATED TEMPERATURE  
SENSOR**

Attorney Docket No.: **SMQ-088/P6549**

Group Art Unit:

Examiner:

**BOX PATENT APPLICATION**

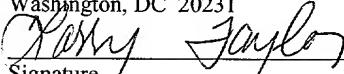
Commissioner for Patents

Washington, D.C. 20231

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Signature

Larry Taylor

Please Print Name of Person Signing

**PRELIMINARY AMENDMENT**

Dear Sir:

Preliminary to examination of the above-referenced patent application, please amend the application as follows:

**In the Specification:**

On page 1, line 3 please add the following paragraph with heading:

**Reference to Related Applications**

The present invention relates to five other applications filed on the same date: A Method and System for Monitoring and Profiling an Integrated Circuit Die Temperature (Atty. Docket: SMQ-087/P6548), A Controller for Monitoring Temperature (Atty. Docket: SMQ-089/P6550), Quantifying a Difference Between Nodal Voltages (Atty. Docket: 03226.116001/P6348), Low Voltage Temperature Independent and Temperature Dependent Voltage Generator (Atty. Docket: 03226.112001/P6322) and Temperature Calibration Using On-Chip Electrical Fuses (Atty. Docket: 03226.108001/P6216).

TELETYPE DE 932

**REMARKS**

The above amendment introduces no new subject matter. Entry of the foregoing Preliminary Amendment is in order and requested. If there are any questions regarding the proposed amendment to the application, we invite the Examiner to call Applicants' attorney at the telephone number below.

Respectfully submitted,

LAHIVE & COCKFIELD, LLP

  
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Date: February 19, 2002

**“VERSION WITH MARKINGS TO SHOW CHANGES MADE”**

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INVENTOR'S DRAFT